

VDS	RDS(on)	ID@25℃
1200V	140mΩ	17A

Applications:

- Solar Inverters
- Switch Mode Power Supplies
- High Voltage DC/DC Converters
- EV Charging
- Motor Drives

Features:

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Easy to Parallel and Simple to Drive
- Avalanche Ruggedness

Benefits:

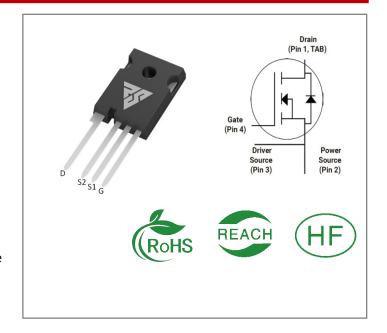
- Higher System Efficiency
- Reduced Cooling Requirements
- Increased Power Density
- Increased System Switching Frequency

Ordering Information

Part Number	Package	Marking	Packing	Qty.	
RSM120160Z	TO-247-4	RSM120160Z	Tube	30 PCS	

Maximum Ratings (TJ= 25 ℃ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
VDSmax	Drain - Source Voltage	1200	V	VGS=0V,ID =100μA	
VGSmax	Gate - Source Voltage	-8/+22	. V Absolute maximum values		
VGSop	Gate - Source Voltage	-4/+18	V	Recommended operational values	
ID	Continuous Drain Current	17 12	А	VGS=18V, TC =25°C VGS=18V, TC =100°C	
ID(pulse)	Pulsed Drain Current	39	А	Pulse width tp limited by TJmax	
PD	Power Dissipation	83	W	TC =25℃, TJ =175℃	
TL	Solder Temperature	260	$^{\circ}$ C		
TJ, Tstg	Operating Junction and StorageTemperature	-55 to + 175	$^{\circ}$ C		





Electrical Characteristics (TJ= 25°C unless otherwise specified)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	Note
V(BR)D SS	Drain-Source Breakdown Voltage	1200			V	VGS=0V,ID =100uA	
) (CC(II)	Gate Threshold	1.9	2.6	4.0	.,	VGS= VDS, IDS=2.5mA, TC =25°C	
VGS(th)	Voltage		1.8		V	VGS= VDS, IDS=2.5mA, TC =175℃	
IDSS	Zero Gate Voltage Drain Current		1	100	μА	VDS= 1200V, VGS=0V	
IGSS	Gate-Source Leakage Current		10	250	nA	VGS=22V, VDS= 0V	
RDS(on)	Drain-Source on-state		140	185	mΩ	VGS=18V, ID =8.5A, TC =25℃	
KD3(0H)	Resistance		248	300	11152	VGS=18V, ID =8.5A, TC =175℃	
Ciss	Input Capacitance		612			VGS=0V, VDS=1000 V,	
Coss	Output Capacitance		34.5		pF	f=1MHz, VAC=25 mV	
Crss	Reverse Transfer Capacitance		8.77				
EON	Turn-On Switching Energy		305		. uJ	VDS =800V, VGS =-4/18V, ID =8.5A, RG(ext) = 2.5Ω,	
EOFF	Turn-Off Energy		48		4,5	L= 100μH	
td(on)	Turn-On Delay Time		7				
tr	Rise Time		30		ns	VDS =800V, VGS =-4/18 V ID = 8.5A, RG(ext) =2. 5 Ω,	
td(off)	Turn-Off Delay Time		16		115	$RL = 20\Omega$	
tf	Fall Time		22				
RG(int)	Internal Gate Resistance		5		Ω	f=1 MHz, VAC=25mV	
Qgs	Gate to Source Charge		7.8				
Qgd	Gate to Drain Charge		12.1		nC	VDS=800V, VGS=-4/18V ID =8.5A	
Qg	Total Gate Charge		42.5				



Reverse Diode Characteristics (TJ= 25°C unless otherwise specified)

Symbol	Parameter	Тур.	Max	Unit	Test Conditions	Note
VCD	Die de Fernand Veltere	4.2 V		٧	VGS=-4V, ISD = 4.2A, TJ = 25℃	
VSD	Diode Forward Voltage			V	VGS=-4V, ISD= 4.2 A, TJ= 175℃	
IS	Continuous Diode Forward Current		17	Α	TC= 25℃	
trr	Reverse Recovery time	20		ns		
Qrr	Reverse Recovery Charge	29		nC	ISD= 8.5 A, VR = 800V	
Irrm	Peak Reverse Recovery Current	2.5		Α		

Thermal Characteristics (TJ= 25℃ unless otherwise specified)

Symbol	Symbol Parameter		Unit	Test Conditions	Not e	
RθJC	Thermal Resistance from Junction to Case	1.75	°C/W			
RθJA	Thermal Resistance From Junction to Ambient	40	C/ VV			

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Typical Feature Curve

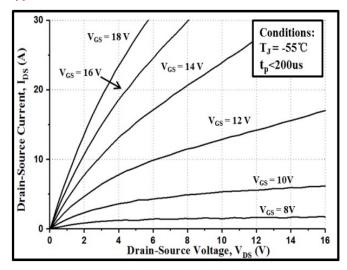


Figure 1. Output Characteristics T_J = -55°C

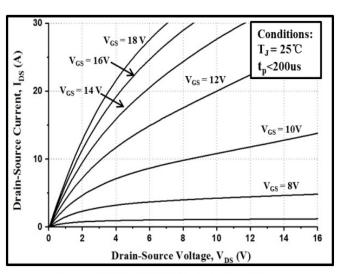


Figure 2. Output Characteristics T_J = 25°C

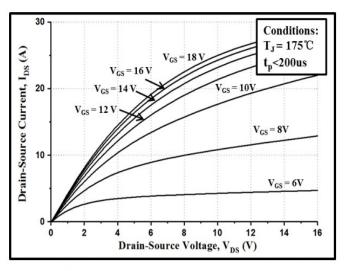


Figure 3. Output Characteristics T₁ = 175 °C

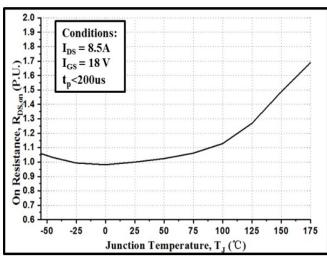


Figure 4. Normalized On-Resistance vs. Temperature

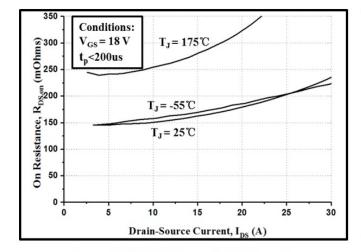


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

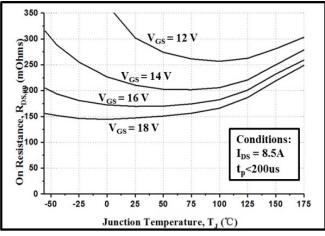


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

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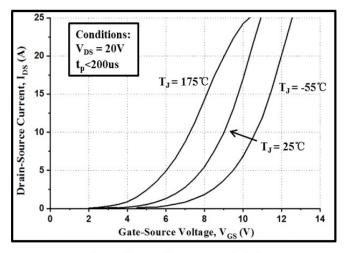


Figure 7. Transfer Characteristic for Various Junction Temperatures

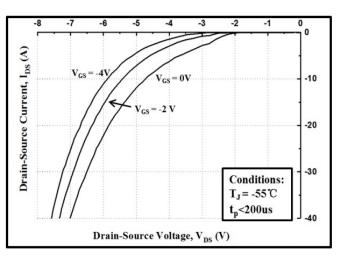


Figure 8. Body Diode Characteristic at -55°C

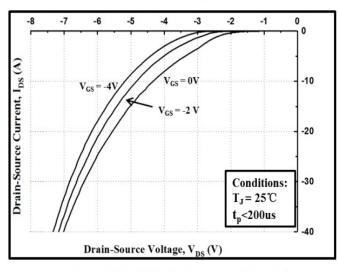


Figure 9. Body Diode Characteristic at 25°C

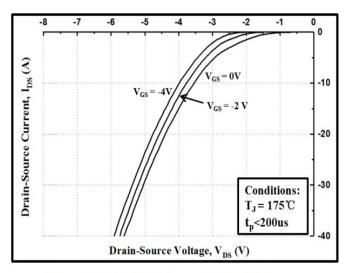


Figure 10. Body Diode Characteristic at 175 ℃

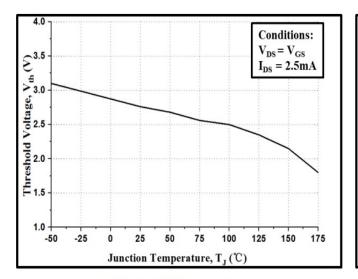


Figure 11. Threshold Voltage vs. Temperature

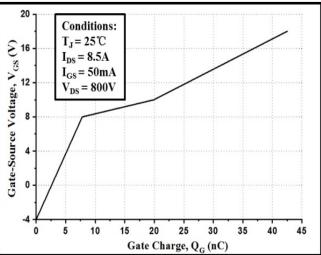
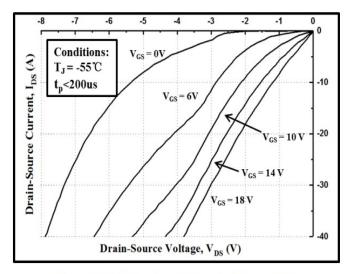


Figure 12. Gate Charge Characteristics

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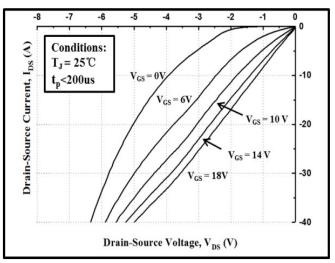
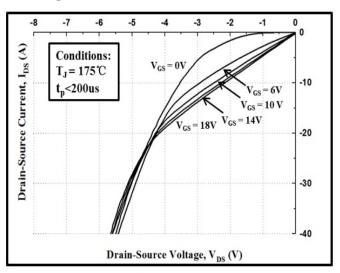


Figure 13. 3rd Quadrant Characteristic at -55°C

Figure 14. 3rd Quadrant Characteristic at 25°C



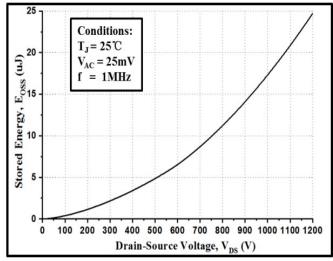
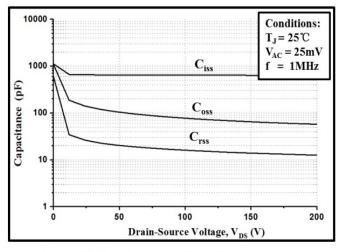


Figure 15. 3rd Quadrant Characteristic at 175 °C

Figure 16. Output Capacitor Stored Energy



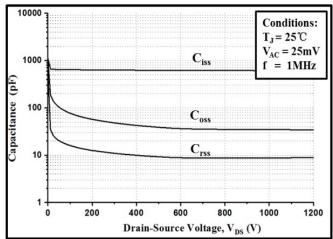


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

Figure 18. Capacitances vs. Drain-Source Voltage (0 - 1200V)

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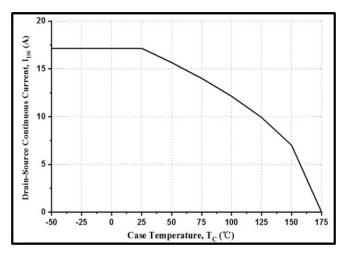


Figure 19. Continuous Drain Current Derating vs.

Case Temperature

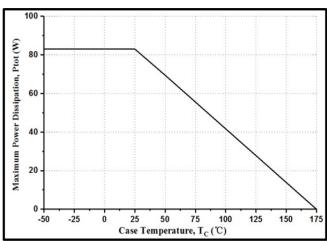


Figure 20. Maximum Power Dissipation Derating vs.

Case Temperature

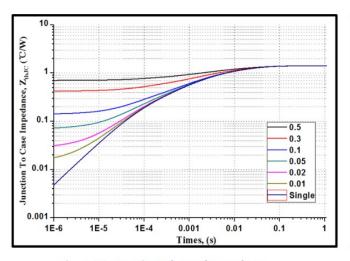


Figure 21. Transient Thermal Impedance (Junction - Case)

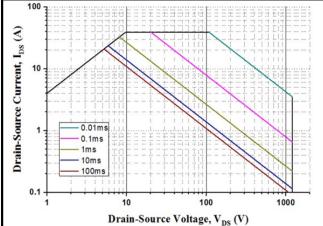
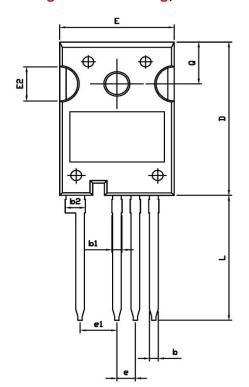
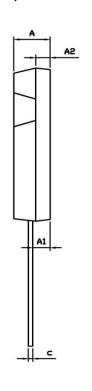


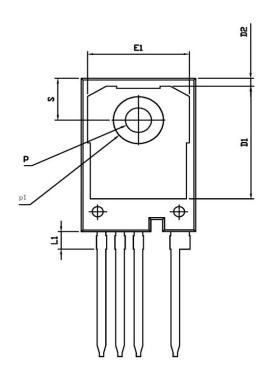
Figure 22. Safe Operating Area



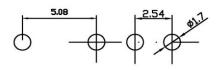
Package outline drawing(TO-247-4 Unit: mm)







RECOMMENDED LAND PATTERN



UNIT: mm

	MIN	NOM	MAX
A	4.80	5.00	5. 20
A1	2. 25	2.40	2.45
A2	1.85	2.00	2. 15
b	1.05	1.20	1. 35
b1	1.00	1.30	1.60
b2	2.35	2.65	2.95
С	0.50	0.60	0.70
D	22. 34	22.54	22.74
D1	16.00	16. 50	17.00
D2	0.97	1.17	1.37
е	2.34	2.54	2.74
e1	4.88	5.08	5. 28
Е	15.60	15.80	16.00
E1	13.50	14.00	14.50
E2	4.80	5.00	5. 20
L	18.08	18.38	18.68
L1	2.38	2.58	2.78
р	3. 50	3.60	3. 70
p1	6.60	6.80	7.00
Q	6.00	6. 15	6. 30
S	6.00	6. 15	6. 30



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